## GaN on SiC HEMT Pulsed Power Transistor

## $15 \mathrm{~W}, \mathrm{DC}-3.5 \mathrm{GHz}$

## Features

- GaN on SiC Depletion Mode Transistor


## MAGX-000035-015000 (Flanged)

- Common-Source Configuration
- Broadband Class AB Operation
- Thermally Enhanced Package (Flanged: Cu/W, Flangeless: Cu )
- RoHS* Compliant
- +50V Typical Operation
- MTTF $=600$ years $\left(\mathrm{T}_{J}<200^{\circ} \mathrm{C}\right)$


## Primary Applications

- Commercial Wireless Infrastructure (WCDMA, LTE, WiMAX)
- Air Traffic Control Radar - Commercial
- Weather Radar - Commercial
- Military Radar - Military
- Public Radio
- Industrial, Scientific and Medical
- SATCOM
- Instrumentation


## Description

The MAGX-000035-01500X is a gold-metalized unmatched Gallium Nitride (GaN) on Silicon Carbide RF power transistor suitable for a variety of RF power amplifier applications. Using state of the art wafer fabrication processes, these high performance transistors provide high gain, efficiency, bandwidth, and ruggedness over multiple octave bandwidths for today's demanding application needs.

The MAGX-000035-01500X is constructed using a thermally enhanced flanged (Cu/W) or flangeless $(\mathrm{Cu})$ ceramic package which provides excellent thermal performance. High breakdown voltages allow for reliable and stable operation in extreme mismatched load conditions unparalleled with older semiconductor technologies.

MAGX-000035-01500S (Flangeless)

## Ordering Information

| Part Number | Description |
| :---: | :---: |
| MAGX-000035-015000 | Flanged, Bulk Packaging |
| MAGX-000035-01500S | Flangeless, Bulk Packaging |
| MAGX-L20035-015000 | Sample Board <br> $(1.2-1.4 \mathrm{GHz}$, Flanged $)$ |
| MAGX-L20035-01500S | Sample Board <br> $(1.2-1.4 \mathrm{GHz}$, Flangeless $)$ |

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# MAGX-000035-015000 <br> MAGX-000035-01500S 

## GaN on SiC HEMT Pulsed Power Transistor

$15 \mathrm{~W}, \mathrm{DC}$ - 3.5 GHz

## Electrical Specifications ${ }^{1}$ : Freq. $=1.2$-1.4 GHz, $\mathrm{T}_{\mathrm{A}}=\mathbf{2 5}^{\circ} \mathrm{C}$

| Parameter | Test Conditions | Symbol | Min. | Typ. | Max. | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| RF Functional Tests: $\mathrm{V}_{\mathrm{DD}}=50 \mathrm{~V}, \mathrm{I}_{\mathrm{DQ}}=15 \mathrm{~mA}, 1 \mathrm{~ms}$ Pulse, 10\% Duty |  |  |  |  |  |  |
| Output Power | $\mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$ | Pout | 15.0 | 17.7 | - | W |
| Power Gain | $\mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$ | $\mathrm{G}_{\mathrm{p}}$ | 14.8 | 15.5 | - | dB |
| Drain Efficiency | $\mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$ | $\eta_{\mathrm{D}}$ | 55 | 63 | - | \% |
| Droop | $\mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$ | Droop | - | 0.1 | 0.4 | dB |
| Load Mismatch Stability | $\mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$ | VSWR-S | - | 5:1 | - | - |
| Load Mismatch Tolerance | $\mathrm{P}_{\mathrm{IN}}=0.5 \mathrm{~W}$ | VSWR-T | - | 10:1 | - | - |

Electrical Characteristics: $\mathrm{T}_{\mathrm{A}}=\mathbf{2 5}^{\circ} \mathrm{C}$

| Parameter | Test Conditions | Symbol | Min. | Typ. | Max. | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DC Characteristics |  |  |  |  |  |  |
| Drain-Source Leakage Current | $V_{G S}=-8 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=175 \mathrm{~V}$ | $\mathrm{l}_{\mathrm{DS}}$ | - | - | 750 | $\mu \mathrm{A}$ |
| Gate Threshold Voltage | $V_{D S}=5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=2 \mathrm{~mA}$ | $\mathrm{V}_{\text {GS (TH) }}$ | -5 | -3 | -2 | V |
| Forward Transconductance | $V_{D S}=5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=500 \mathrm{~mA}$ | $\mathrm{G}_{\mathrm{M}}$ | 0.35 | - | - | S |
| Dynamic Characteristics |  |  |  |  |  |  |
| Input Capacitance | $V_{D S}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | $\mathrm{C}_{\text {Iss }}$ | - | 4.4 | - | pF |
| Output Capacitance | $V_{D S}=50 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | Coss | - | 1.9 | - | pF |
| Reverse Transfer Capacitance | $\mathrm{V}_{\mathrm{DS}}=50 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | $\mathrm{C}_{\text {RSS }}$ | - | 0.2 | - | pF |

## Correct Device Sequencing

## Turning the device ON

1. Set $\mathrm{V}_{\mathrm{GS}}$ to the pinch-off ( $\mathrm{V}_{\mathrm{P}}$ ), typically -5 V .
2. Turn on $\mathrm{V}_{\mathrm{DS}}$ to nominal voltage ( +50 V ).
3. Increase $V_{G S}$ until the $I_{D S}$ current is reached.
4. Apply RF power to desired level.

## Turning the device OFF

1. Turn the RF power off.
2. Decrease $\mathrm{V}_{\mathrm{GS}}$ down to $\mathrm{V}_{\mathrm{P}}$.
3. Decrease $\mathrm{V}_{\mathrm{DS}}$ down to 0 V .
4. Turn off $\mathrm{V}_{\mathrm{Gs}}$.

GaN on SiC HEMT Pulsed Power Transistor
$15 \mathrm{~W}, \mathrm{DC}$ - 3.5 GHz
Absolute Maximum Ratings ${ }^{2,3,4}$

| Parameter | Absolute Max. |
| :---: | :---: |
| Input Power | PiN (nominal) +3 dB |
| Drain Supply Voltage, $\mathrm{V}_{\mathrm{DD}}$ | +65 V |
| Gate Supply Voltage, $\mathrm{V}_{\mathrm{GG}}$ | -8 V to 0 V |
| Supply Current, $\mathrm{IDD}^{\text {d }}$ | 800 mA |
| Power Dissipation ( $\mathrm{Pavg}^{\text {) , Pulsed }}$ @ $85^{\circ} \mathrm{C}$ | 10.3 W |
| MTTF ( $\mathrm{T}_{3}<200^{\circ} \mathrm{C}$ ) | 600 years |
| Junction Temperature ${ }^{5}$ | $200^{\circ} \mathrm{C}$ |
| Operating Temperature | $-40^{\circ} \mathrm{C}$ to $+95^{\circ} \mathrm{C}$ |
| Storage Temperature | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Mounting Temperature | See solder reflow profile |
| ESD Min. - Charged Device Model (CDM) | 150 V |
| ESD Min. - Human Body Model (HBM) | 500 V |

2. Operation of this device above any one of these parameters may cause permanent damage.
3. Channel temperature directly affects a device's MTTF. Channel temperature should be kept as low as possible to maximize lifetime.
4. For saturated performance it is recommended that the sum of $\left(3^{*} \mathrm{~V}_{\mathrm{DD}}+\mathrm{abs}\left(\mathrm{V}_{\mathrm{GG}}\right)\right)<175 \mathrm{~V}$.
5. Junction Temperature $\left(T_{J}\right)=T_{C}+\Theta_{J C} *\left((V * I)-\left(P_{\text {out }}-P_{\text {IN }}\right)\right)$

Typical transient thermal resistances:
1 ms pulse, $10 \%$ duty cycle, $\Theta_{\mathrm{Jc}}=5.0^{\circ} \mathrm{C} / \mathrm{W}$
For $\mathrm{T}_{\mathrm{C}}=85^{\circ} \mathrm{C}$,
$\mathrm{T}_{\mathrm{J}}=132^{\circ} \mathrm{C} @ 50 \mathrm{~V}, 520 \mathrm{~mA}-\mathrm{pk}, \mathrm{P}_{\text {OUt }}=17.0 \mathrm{~W}, \mathrm{P}_{\text {IN }}=0.5 \mathrm{~W}$

# MAGX-000035-015000 <br> MAGX-000035-01500S 

GaN on SiC HEMT Pulsed Power Transistor
$15 \mathrm{~W}, \mathrm{DC}$ - 3.5 GHz
Rev. V1
Test Fixture Assembly (1.2-1.4 GHz, 1 ms Pulse, 10\% Duty, $\mathrm{V}_{\mathrm{DD}}=50 \mathrm{~V}$, Idq $=15 \mathrm{~mA}$ )


## Parts List

| Reference Designator | Part | Vendor |
| :--- | :--- | :--- |
| C4 | $0402,5.1 \mathrm{pF}, \pm 0.1 \mathrm{pF}$ | ATC |
| C15 | $0603,6.8 \mathrm{pF}, \pm 0.1 \mathrm{pF}$ | ATC |
| C2 | $0603,82 \mathrm{pF}, \pm 10 \%$ | ATC |
| C16 | $0603,100 \mathrm{pF}, \pm 10 \%$ | ATC |
| C1, C10 | $0402,1000 \mathrm{pF}, 100 \mathrm{~V}, 5 \%$ | ATC |
| C8 | $0603,30 \mathrm{pF}, \pm 10 \%$ | ATC |
| C13 | $0805,1 \mu \mathrm{~F}, 100 \mathrm{~V}, \pm 20 \%$ | ATC |
| C14 | $0402,12 \mathrm{pF}, \pm 10 \%$ | ATC |
| C17 | $100 \mu \mathrm{~F}, 160 \mathrm{~V}$, Electrolytic Capacitor | Panasonic |
| C3, C6, C7, C9, C11, C12, R2 | Do Not Populate |  |
| R3 | $240 \Omega, 0603,5 \%$ | Panasonic |
| L1, R1 | $1.0 \Omega, 0402,5 \%$ | Panasonic |
| R4 | $1.0 \Omega, 1206,5 \%$ | Panasonic |
| R5 | $10 \Omega, 0402,5 \%$ | Panasonic |
| L3, L6 | $0402,3.9 \mathrm{nH}, 2 \%$ | Coilcraft |
| L2, R6 | $0402,0.0 \Omega$ Resistor | Panasonic |
| J1, J2 | SMA Connector | Tyco Electronics |

# MAGX-000035-015000 <br> MAGX-000035-01500S 

GaN on SiC HEMT Pulsed Power Transistor
15 W, DC - 3.5 GHz

## Application Section

## Typical Performance Curves

1.2-1.4 GHz, 1 ms Pulse, $10 \%$ Duty, $\mathrm{V}_{\mathrm{DD}}=50 \mathrm{~V}$, Idq $=15 \mathrm{~mA}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

Output Power and Gain Vs. Input Power


Drain Efficiency Vs. Output Power


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## Outline Drawing MAGX-000035-015000 (Flanged)



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$15 \mathrm{~W}, \mathrm{DC}-3.5 \mathrm{GHz}$

## Outline Drawing MAGX-000035-01500S (Flangeless)



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[^0]:    * Restrictions on Hazardous Substances, European Union Directive 2002/95/EC.

